

Search Notes**Application/Control No.**

10/584,839

Examiner

/Yonel Beaulieu/

**Applicant(s)/Patent under
Reexamination**

CHO ET AL.

Art Unit

3661

SEARCHED

Class	Subclass	Date	Examiner
701	117-119	7/17/2010	YB
	200-202		
	208		
	211		
342	357.09	7/17/2010	YB
	357.1		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
Searched above		7/17/2010	YB

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR